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STATEMENT BY APPLICANT			PPLICANT	First Named Inventor	Martin Hirsch	
				Art Unit	1793	
(Use as many sheets as necessary)			ecessary)	Examiner Name	Not Yet Assigned	
Sheet	1	of	3	Attorney Docket Number	20941/0211433-US0	

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Signature /Mark L. Shevin/ Considered 07/27/2009	Examiner Signature	/Mark L. Snevin/	Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. * CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Petent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

